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L9 and BIST

3

09 / 747,734
Updated search

Examiner:
T. R. Sundaram

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Set Name Query
side by side

DB=USPT; THES=ASSIGNEE; PLUR=YES; OP=ADJ

		<u>Hit Count</u>	<u>Set Name</u>
			result set
<u>L14</u>	L9 and BIST	3	<u>L14</u>
<u>L13</u>	L9 and predict\$3 same (fail\$3)	0	<u>L13</u>
<u>L12</u>	L9 and predict\$3 and (fail\$3)	22	<u>L12</u>
<u>L11</u>	L9 and predict with (fail\$3)	0	<u>L11</u>
<u>L10</u>	L9 and predict with failure	0	<u>L10</u>
<u>L9</u>	L8 and (ris\$3 or fall\$3) with time	107	<u>L9</u>
<u>L8</u>	L7 and test ADJ signal	248	<u>L8</u>
<u>L7</u>	L6 and pulse ADJ width	958	<u>L7</u>
<u>L6</u>	(IC or integrated ADJ circuit) with (chip or die or dice) and test\$3 with (signal or circuit)	10476	<u>L6</u>
<u>L5</u>	L3 and (predict\$3 or forecast\$3) with fail\$3	3	<u>L5</u>
<u>L4</u>	L3 and predict\$3 with fail\$3	3	<u>L4</u>
<u>L3</u>	L2 and (ris\$3 or fall\$3) with signal	1271	<u>L3</u>
<u>L2</u>	L1 and pulse ADJ width	2848	<u>L2</u>
<u>L1</u>	(IC or integrated ADJ circuit) and test\$3 with (signal or circuit)	28140	<u>L1</u>

END OF SEARCH HISTORY